

AFM and SEM investigations of ion beam synthesized Mg₂Si precipitates in Si substrates

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Raman scattering characterization of ion-beam synthesized Mg₂Si. 1, Influence of the technological conditions on the formation of the Mg₂Si in(100) Si matrix

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Solid phase and ion beam epitaxial crystallization of Si implanted with Zn and Pb ions

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Structural investigations of ion beam synthesized [beeta]-FeSi₂

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Study of ion implanted Fe depth distribution in Si after pulsed ion beam treatment

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